# **Power MOSFET**

# 30 V, 59 A, Single N-Channel, SO-8FL

### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Low RG
- These are Pb-Free Devices

#### **Applications**

- Refer to Application Note AND8195/D
- CPU Power Delivery
- DC-DC Converters

### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise stated)

	, ,			,	
Para	Parameter			Value	Unit
Drain-to-Source Volta	age		$V_{DSS}$	30	V
Gate-to-Source Volta	age		$V_{GS}$	±20	V
Continuous Drain Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	13.5 9.7	А
Power Dissipation R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	2.16 1.1	W
Continuous Drain Current R <sub>θJA</sub> ≤10 s		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	21.8 15.7	A
Power Dissipation $R_{\theta JA} \leq 10 \text{ s}$	Steady State	T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	5.7 2.9	W
Continuous Drain Current R <sub>0JA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	I <sub>D</sub>	8.6 6.2	А
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C T <sub>A</sub> = 85°C	P <sub>D</sub>	0.87 0.45	W
Continuous Drain Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	I <sub>D</sub>	59 42.5	А
Power Dissipation R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 25°C T <sub>C</sub> = 85°C	P <sub>D</sub>	41.7 21.7	W
Pulsed Drain Current	t <sub>p</sub> = 10 μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	177	Α
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C	
Source Current (Body Diode)		I <sub>S</sub>	35	Α	
Drain to Source dV/dt		dV/dt	6	V/ns	
Single Pulse Drain–to–Source Avalanche Energy (V <sub>DD</sub> = 24 V, V <sub>GS</sub> = 10 V, I <sub>L</sub> = 25.6 A, L = 0.3 mH, R <sub>G</sub> = 25 $\Omega$ )		EAS	98	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

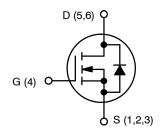
- 1. Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
- 2. Surface-mounted on FR4 board using the minimum recommended pad size.



### ON Semiconductor®

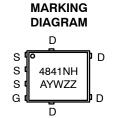
### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
30 V	$6.72~\mathrm{m}\Omega$ @ $10~\mathrm{V}$	50 A
30 V	11.6 mΩ @ 4.5 V	59 A



**N-CHANNEL MOSFET** 





A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NTMFS4841NHT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4841NHT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	3	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	57.8	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	143.5	°C/ <b>VV</b>
Junction–to–Ambient (t≤10 s)	$R_{ heta JA}$	22.1	

## FI FCTRICAL CHARACTERISTICS (T = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS						•	
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu A$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				28		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25 °C			1	μΑ
		V <sub>DS</sub> = 24 V	T <sub>J</sub> = 125°C			10	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	; = ±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 250 μΑ	1.5	2.1	2.5	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				5.6		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to	I <sub>D</sub> = 30 A		4.8	6.72	- mΩ
		11.5 V	I <sub>D</sub> = 15 A		4.8		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		8.8	11.6	
			I <sub>D</sub> = 15 A		8.5		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 50 A			57		S
CHARGES AND CAPACITANCES	•					1	
Input Capacitance	C <sub>ISS</sub>			939	1565	2113	
Output Capacitance	C <sub>OSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V		195	325	439	pF
Reverse Transfer Capacitance	C <sub>RSS</sub>			103.8	173	242.2	1
Total Gate Charge	Q <sub>G(TOT)</sub>				11.3	15.82	1
Threshold Gate Charge	Q <sub>G(TH)</sub>		45.11 00 A		1.4	2.1	nC
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 3.5 \text{ V}$	15 V; I <sub>D</sub> = 30 A		5.3	7.9	
Gate-to-Drain Charge	$Q_{GD}$				4.5	6.8	
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS} = 11.5 \text{ V}, V_{DS} = 15 \text{ V},$ $I_D = 30 \text{ A}$			24.4	33	nC
SWITCHING CHARACTERISTICS (Note 4)							
Turn-On Delay Time	t <sub>d(ON)</sub>				12.1	18.1	
Rise Time	t <sub>r</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 1	5 V. In = 15 A		23.3	34.9	1
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$R_G = 3.0 \Omega$			14.1	21.1	ns ns
Fall Time	t <sub>f</sub>				4.9	7.3	
Turn-On Delay Time	t <sub>d(ON)</sub>				7.2	10.7	
Rise Time	t <sub>r</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			20.6	30.9	ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				21.9	32.9	
Fall Time	t <sub>f</sub>				2.9	4.4	

- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

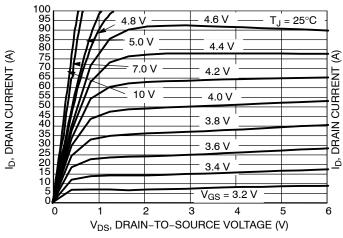
### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS									
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.86	1.2			
		I <sub>S</sub> = 30 A	T <sub>J</sub> = 125°C		0.71		V		
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A}/\mu\text{s,}$ $I_{S} = 30 \text{ A}$			18.8				
Charge Time	t <sub>a</sub>				11.4		ns		
Discharge Time	t <sub>b</sub>				7.4				
Reverse Recovery Charge	Q <sub>RR</sub>				6.7	26.7	nC		
PACKAGE PARASITIC VALUES									
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.93		nH		
Drain Inductance	L <sub>D</sub>				0.005				
Gate Inductance	L <sub>G</sub>				1.84				
Gate Resistance	R <sub>G</sub>				0.90		Ω		

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

### **TYPICAL CHARACTERISTICS**

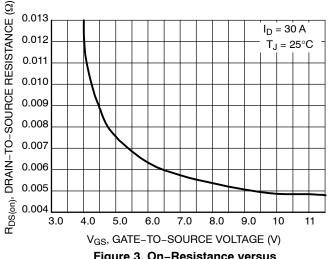
90



80
70
60
50
40  $T_C = 25^{\circ}C$ 10  $T_C = 125^{\circ}C$ 10  $T_C = -55^{\circ}C$ 

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



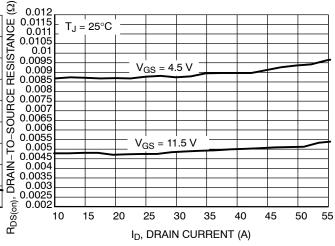
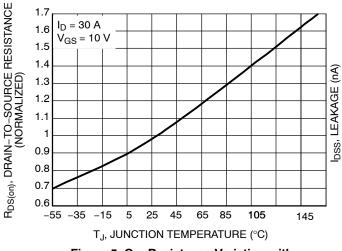


Figure 3. On-Resistance versus Gate-to-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage



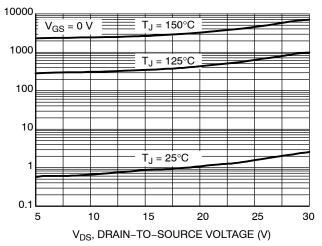
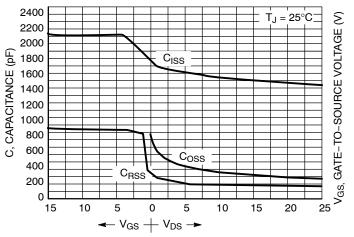


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current versus Voltage

### **TYPICAL CHARACTERISTICS**



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (V)

Figure 7. Capacitance Variation

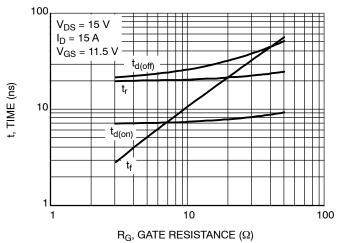


Figure 9. Resistive Switching Time Variation versus Gate Resistance

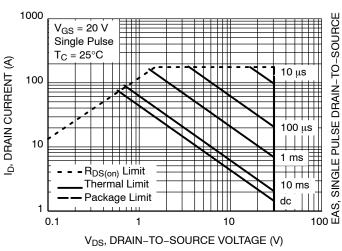


Figure 11. Maximum Rated Forward Biased Safe Operating Area

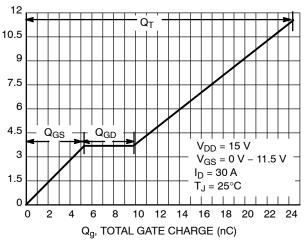


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Gate Charge

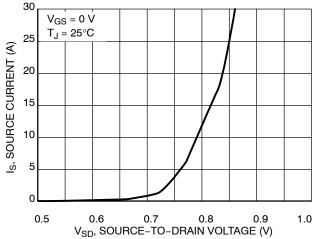
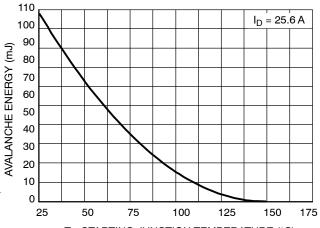


Figure 10. Diode Forward Voltage versus

Current



T<sub>J</sub>, STARTING JUNCTION TEMPERATURE (°C)

Figure 12. Maximum Avalanche Energy versus Starting Junction Temperature

### **TYPICAL CHARACTERISTICS**

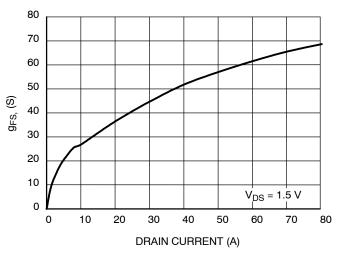


Figure 13. G<sub>FS</sub> versus Drain Current

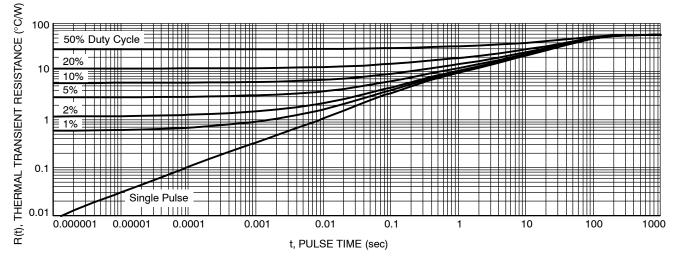
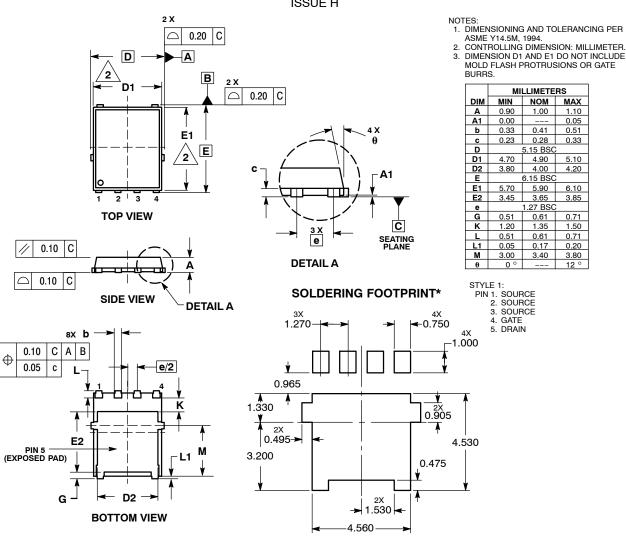


Figure 14. Thermal Resistance

### PACKAGE DIMENSIONS





\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

ON Semiconductor and under a registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC owns the rights to a number of patents, trademarks, one semiconductor and are registered traderinats of semiconductor Components mustures. Let (ScillLC) scill science of the copyrights, trade secrets, and other intellectual property. A listing of SCILLC's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent—Marking.pdf. SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surviced implant into the policy or other applications intended for surviced implant into the policy or other applications when the failure of the SCILLC product could create a situation when surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

### **PUBLICATION ORDERING INFORMATION**

#### LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910 Japan Customer Focus Center

Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

1.10

0.05

0.51

0.33

5.10

4.20

6.10

3.85

0.71

1.50

0.71

0.20

3.80

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative